

<b>Notice of References Cited</b>	Application/Control No. 10/584,202		Applicant(s)/Patent Under Reexamination DIVOUX, CLAIRE	
	Examiner KARL I.E. TAMAI		Art Unit 2834	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2007/0137989	06-2007	Divoux et al.	200/005.00A
*	B	US-2007/0120438	05-2007	Divoux, Claire	310/309
*	C	US-2006/0291129	12-2006	Chappaz et al.	361/207
*	D	US-2002/0171327	11-2002	Miller et al.	310/309
*	E	US-2003/0168928	09-2003	Clark et al.	310/309
*	F	US-2007/0103843	05-2007	Charton et al.	361/233
*	G	US-6,384,952	05-2002	Clark et al.	359/224.1
*	H	US-6,220,561	04-2001	Garcia, Ernest J.	248/487
*	I	US-5,408,355	04-1995	Rauch et al.	359/298
*	J	US-5,867,302	02-1999	Fleming, James G.	359/291
*	K	US-3,886,310	05-1975	Guldborg et al.	348/771
*	L	US-6,760,144	07-2004	Hill et al.	359/290
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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